

Application No. 10/042,336

Please substitute the paragraph starting on page 7, line 24 and continuing to page 8 with the following:

Turning next to FIG.2, a detailed illustration of the substrate size monitoring system of the present invention is illustrated showing a tray 55 in an initially closed position as indicated by tray home signal line 120 and is bracketed by machine guides 93 and 94. A sensor 92 is positioned below machine guide 93 and is in communication with controller 29 to give off a change of direction signal 130. Tray 55 includes side guides 90 and 91 that are adjusted in accordance with the size of substrates or sheets placed into the tray. Tray 55 also includes a stud 95 loaded by spring 96. Stud 95 has a flag 97 attached thereto, such that, movement of the stud causes the flag to rotate in a clockwise or counter-clockwise direction.

[Please substitute the paragraph starting on page 8, line 3 with the following paragraph:]

As shown in FIG. 2, Tray 55 is initially in a home position as indicated by tray home signal 128. As the tray is pulled out from the machine the tray home signal 128 is changed as indicated by line 120 and after the tray is returned to the home position the tray home signal is back at 128. In FIG. 2, side guides 90 and 91 have not been adjusted and flag 97 does not cover sensor 92 during withdrawal or insertion of tray 55 into the machine. This is indicated by change detection signal 130 being in a straight line continuously during movement of the tray.